


Search Notes 	Application/Control No. 10560517	Applicant(s)/Patent Under Reexamination ALI-HACKL ET AL.
	Examiner HUY D NGUYEN	Art Unit 2617

SEARCHED			
Class	Subclass	Date	Examiner
370	350, 318	10/23/2008	HN
455	13.4, 522, 127.1	10/23/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	10/23/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--